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PCN Number:				2/09/2016				
	TPS57140-Q1							
Customer Contact:	PCN Manager			Dej	ept: Quality Services			
Change Type:					111 6			
Assembly Site		Design		\perp		Bump Site		
Assembly Process		Data Sheet				Bump Material		
Assembly Material		Part number	cnange	<u>H</u>		Bump Process		
Mechanical Specifi		Test Site Test Process	,	\vdash		r Fab Site r Fab Materials		
Packing/Shipping/	Labelling	Test Process		H		er Fab Materials Fer Fab Process		
Notification Details								
Description of Change:								
Texas Instruments Incorporated is announcing an information only notification.								
The product datasheet(s) is updated as seen in the change revision history below:								
					4	🎝 Ţex	AS TRUMENTS	
TPS57140-Q1					`	INS	TRUMENTS	
SLVSAP3C – DECEMBER 2010 – REVISED JANUARY 2016 www.ti.com								
Changes from Revision B (March 2013) to Revision C Page								
Added three AEC-Q100 results to features bullet list — temperature grade, HBM and CDM classification levels								
 Added ESD Ratings table, Feature Description section, Device Functional Modes, Application and Implementation 								
section, Power Supply Recommendations section, Layout section, Device and Documentation Support section, and Mechanical, Packaging, and Orderable Information section								
Added a capacitor between the COMP pin and ground in the Simplified Schematic								
Reworded the PH output voltage specifications and specified the maximum value for T _J = –40°C in the <i>Absolute</i>								
Maximum Ratings table for clarity								
Deleted the R _{BJA} values for the custom board and changed the other values in the <i>Thermal Information</i> table								
Reworded the PWRGD switching threshold specifications in the <i>Electrical Characteristics</i> table for clarity								
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					4	TEX	AS TRUMENTS	
TPS57140-Q1					·	- 1145	DIRUMENTS	
SLVSAP3D - DECEMBER 2010-REVIS	SLVSAP3D – DECEMBER 2010 – REVISED FEBRUARY 2016 www.ti.com							
Changes from Revision C (Ja	anuary 2016) to Revi	sion D					Page	
			th			4 FI-		
 Changed the test condition Characteristics table 	and removed the red	undant values for	the voltage referen	ce pa	ameter in	tne <i>El</i> e	ctricai 5	
- Criaracterior table								
Device Family		Chango Ero	m:		17	hand	је То:	
Device Family TPS57140-Q1		Change Fro				AP3C		
TPS57140-Q1	SLVSAP3				SLVSAP3D			
	hese changes may be reviewed at the datasheet links provided.							
http://www.ti.com/prod			iks provided.					
	<u>Juct/tps5/140-0</u>	<u>1 </u>						
Reason for Change:								
To more accurately reflect device characteristics.								
Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):								
No anticipated impact. This is a specification change announcement only. There are no changes								
to the actual device.								
Changes to product identification resulting from this PCN:								
None.								
Product Affected:	Product Affected:							
TPS57140QDGQRQ1		TE	S57140QDRC	RO1				

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail			
USA	PCNAmericasContact@list.ti.com			
Europe	PCNEuropeContact@list.ti.com			
Asia Pacific	PCNAsiaContact@list.ti.com			
Japan	PCNJapanContact@list.ti.com			